

2019 2nd International Conference on Communication Engineering and Technology

Nagoya Institute of Technology, Nagoya, Japan | 12-15 April, 2019

Submission Deadline: **February 10, 2019**

TOPICS

- Network and Wireless Communication
- VLSI Circuits and Systems Design
- Information Hiding and Watermarking
- Multimedia
- Network and Information Security
- RF Front-End Circuits and Systems
- Intelligent Mobile Device Design
- Coding and Signal Processing
- Wearable Technology
- Microwave/MM-Wave/THz Circuits and System
- Internet of Things and Big data
- Computer Vision and Artificial Intelligence
- 5G Communication and Network
- Green Communication Systems
- Communication Device Modeling
- EMC and Antenna Design



COMMITTEE

Conference Chairs

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KEYNOTE / INVITED SPEAKERS

* Prof. Yonghui Li

University of Sydney, Australia

* Prof. Yutaka Ishibashi

(Chair of IEEE Nagoya Section)

Nagoya Institute of Technology, Japan

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HISTORY

ICCET 2018 Singapore | February 24-26, 2018

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VENUE

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PROCEEDINGS

Accepted (Registered and Presented) papers will be published in the ICCET 2019 proceedings by **IEEE**.

The conference proceedings will be reviewed for inclusion into **IEEE Xplore**, and indexing in **Ei Compendex** and **Scopus** and submitted to Thomson Reuters Conference Proceedings Citation Index (ISI Web of Science) for potential index as well.

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